Notice of References Cited

 $\bullet = \mathfrak{C} \circ \mathfrak{g} = -f$

Application/Control No.

10/541,016

Examiner

Douglas J. Duff

Applicant(s)/Patent Under
Reexamination
GRAHLE ET AL.

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0150489	10-2002	Kim, Deok-Kyeom	418/13
*	В	US-5,879,138	03-1999	Arndt et al.	417/244
*	C	US-5,252,048	10-1993	Fujiwara et al.	418/220
*	D	US-2003/0185696	10-2003	Otto, Dieter	418/152
*	Е	US-6,923,628	08-2005	Otto, Dieter	418/152
*	F	US-6,743,004	06-2004	Otto, Dieter	418/152
*	G	US-6,648,619	11-2003	Otto, Dieter	418/152
*	Н	US-5,976,214	11-1999	Kondoh et al.	75/244
*	-	US-4,248,813	02-1981	Hattori et al.	264/645
*	J	US-3,726,572	04-1973	Beardmore, Geoffrey	384/113
*	К	US-3,622,254	11-1971	LeBlanc, Jr., Joseph A.	418/226
*	L	US-5,548,973	08-1996	Komine et al.	62/469
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 01142287 A	06-1989	Japan	YOSHIDA et al.	
	0	DE 19703499 A1	08-1998	Germany	STRAUS et al.	
	Р	DE 4020082 A1	01-1991	Germany	HERTELL, SIEGFRIED DIPL I	
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

	NOT FAILT DOGINERY						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	٧						
	w						
	x						

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.